

Notice of References Cited	Application/Control No. 10/590,726		Applicant(s)/Patent Under Reexamination NAKADA ET AL.	
	Examiner Tianjie Chen		Art Unit 2627	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0208093 A1	10-2004	Omori et al.	369/044.32
*	B	US-2007/0162917 A1	07-2007	Omori et al.	720/603
*	C	US-2007/0028248 A1	02-2007	Chen et al.	720/601
*	D	US-2006/0218564 A1	09-2006	Kirihara et al.	720/603
*	E	US-2005/0076346 A1	04-2005	Matsumoto et al.	720/601
*	F	US-2004/0261088 A1	12-2004	HSU et al.	720/601
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	Q					
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	T					

NON-PATENT DOCUMENTS

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